

Explorations in low area overhead DFT techniques for sequential BIST

Raik, Jaan; Raidma, Rein; **Ubar, Raimund-Johannes** IEEE NORCHIP 2003 : 21 Norchip Conference : Riga, Latvia, 10-11 November 2003 : proceedings 2003 / p. 220-223 : ill

Fault emulation on FPGA : a feasibility study

Ellervee, Peeter; **Raik, Jaan**; Tihomirov, Valentin IEEE NORCHIP 2003 : 21 Norchip Conference : Riga, Latvia, 10-11 November 2003 : proceedings 2003 / p. 92-95 : ill https://www.researchgate.net/publication/246171898_Fault_Emulation_on_FPGA_A_Feasibility_Study

Test time minimization for hybrid BIST with test pattern broadcasting

Ubar, Raimund-Johannes; Jenihhin, Maksim; **Jervan, Gert**; Peng, Zebo IEEE NORCHIP 2003 : 21 Norchip Conference : Riga, Latvia, 10-11 November 2003 : proceedings 2003 / p. 112-116 : ill <https://www.ida.liu.se/labs/eslab/publications/pap/db/norchip03.pdf>